ISO 11505:2012-12 (E)

Surface chemical analysis - General procedures for quantitative compositional depth profiling by glow discharge optical emission sp ectrometry

Contents

Page

Foreword iv

1 Scope 1

2 Normative references 1

3 Principle 1

4 Apparatus 1
4.1 Glow discharge optical emission spectrometer 1

5 Adjusting the glow discharge spectrometer system settings 3
5.1 General 3
5.2 Setting the discharge parameters of a DC source 4
5.3 Setting the discharge parameters of an RF source 6
5.4 Minimum performance requirements 7

6 Sampling 9

7 Calibration 9
7.1 General 9
7.2 Calibration specimens 9
7.3 Validation specimens 11
7.4 Determination of the sputtering rate of calibration and validation specimens 11
7.5 Emission intensity measurements of calibration specimens 12
7.6 Calculation of calibration equations 12
7.7 Validation of the calibration 12
7.8 Verification and drift correction 13

8 Analysis of test specimens 14
8.1 Adjusting discharge parameters 14
8.2 Setting of measuring time and data acquisition rate 14
8.3 Quantifying depth profiles of test specimens 14

9 Expression of results 15
9.1 Expression of quantitative depth profile 15
9.2 Determination of total coating mass per unit area 15
9.3 Determination of average mass fractions 16

10 Precision 16

11 Test report 16

Annex A (normative) Calculation of calibration constants and quantitative evaluation of depth profiles 17

Annex B (informative) Suggested spectral lines for determination of given elements 31

Bibliography 33